


<b>Search Notes</b> 	<b>Application/Control No.</b> 10576787	<b>Applicant(s)/Patent Under Reexamination</b> NEBASHI ET AL.
	<b>Examiner</b> THIEM PHAN	<b>Art Unit</b> 3729

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SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search Attached	1/13/09	TP

INTERFERENCE SEARCH			
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